

# Polarization Measurement at the ILC

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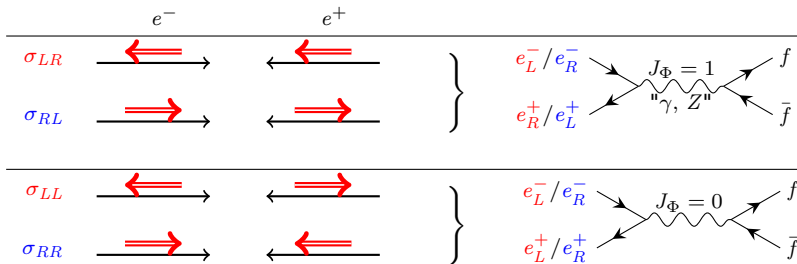
A Graduate Education Program  
of Universität Hamburg  
in Cooperation with DESY



# Polarization at an $e^-e^+$ Collider

## ► Consider only one electron positron pair:

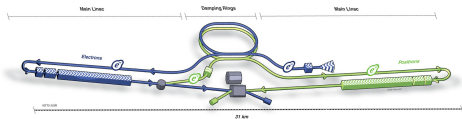
- Helicity is the projection of the spin vector on the direction of motion
- In case of massless particles, helicity is equal to chirality (left and right handedness)
- If  $E_{\text{kin}} \gg E_0 \rightarrow m_e \approx 0$  e.g. ILC:  $E_{\text{kin}}/E_0 \approx \mathcal{O}(10^5 - 10^6)$



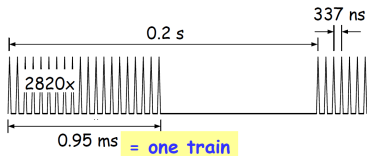
## ► For a bunch of particles the polarization $P$ is defined as:

$$P := \frac{N_R - N_L}{N_R + N_L} \quad \begin{cases} N_R : & \text{The number of right-handed particles} \\ N_L : & \text{The number of left-handed particles} \end{cases}$$

# The International Linear Collider (ILC)



- ▶ Future linear  $e^+e^-$  Collider:  
 $\sqrt{s} \rightarrow 500 \text{ GeV}$  (possible upgrade 1 TeV)
- ▶ Proposed in the Kitakami region,  
Prefecture Iwate, Japan
- ▶  $e^+e^-$  collide in *trains* consisting of  $\approx \mathcal{O}(10^3)$   
*bunches*
- ▶ One *bunch* consists of  $2 \cdot 10^{10}$  particles



# Advantages of Polarized Beams

## ▶ International Linear Collider (ILC)

- ▶  $e^-e^+$  beams are polarized to  $|80\%|$  and  $|30\%|$ , respectively
- ▶ Switch of polarization sign (helicity reversal)  $\rightarrow$  choice of spin configuration

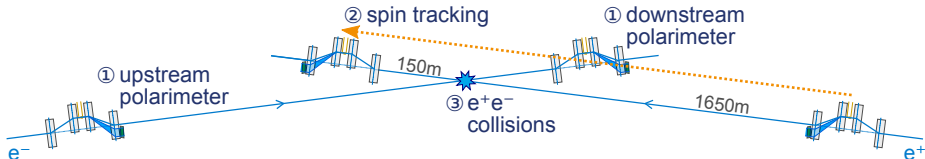
## ▶ Advantages:

- ▶ Sensitive to additional observables (e.g. left-right-asymmetry)
- ▶ Reduction of background processes and simultaneously increase of signal processes
- ▶ Deep insights into the chiral structure of the weak-interaction for known and unknown particle

- $\Rightarrow$  **All event rates depend linearly on the polarization!**
- $\Rightarrow$  **Has to be known as precisely as the luminosity!**
- $\Rightarrow$  **Requirement for a permille-level precision of the luminosity-weighted average polarization**



# ILC Polarimetry Concept for Permilie-Level Polarization Precision



## ▶ The time-resolved beam polarization:

- ▶ Measured with 2 laser-Compton polarimeters before and after the  $e^-e^+$  IP
- ▶ Polarimeter precision  $\Delta P/P = 0.25\%$  from the start
- ▶ Extrapolated to the  $e^-e^+$  IP via spin tracking

## ▶ The luminosity-weighted averaged polarization:

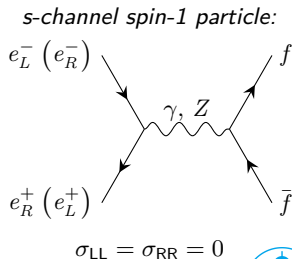
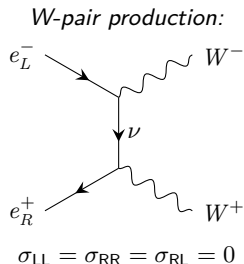
- ▶ Calculated from collision data at the IP
  - ▶ Using the cross section measurement of well known standard model processes
  - ▶ Precision  $\Delta P/P = 0.1\%$  after  $\approx 3$  years of data taking
- ⇒ Focused on in the following

# Physics Processes for Polarization Measurement

- ▶ Unpolarized cross section  $\sigma_0 := \frac{1}{4} \sum \sigma$ 
  - ▶ Higher  $\sigma_0$  increases the event rate
  - ⇒ Increase of statistical polarization precision
- ▶ Left-right-asymmetry  $A_{\text{RL}}^{\text{LR}} := \frac{\sigma_{\text{LR}} - \sigma_{\text{RL}}}{\sigma_{\text{LR}} + \sigma_{\text{RL}}}$ 
  - ▶ Sensitivity to the chiral structure
  - ▶ There are no  $\nu_R$  and  $\bar{\nu}_L$
  - ⇒ Process including a  $W^\pm$  yields high asymmetries

## Examples:

Process	$A_{\text{RL}}^{\text{LR}}$	$\sigma_0[\text{pb}]$
WW	0.991	4.52
Z	0.26	15.1
ZZWWMix	0.973	1.83
ZZ	0.386	0.486
⋮	⋮	⋮



# Polarized Cross Section Calculation: Basic Concept

## Theory:

$$\begin{aligned}\sigma^{\text{theory}}(P_{e-}, P_{e+}) = & \frac{(1-P_{e-})}{2} \frac{(1+P_{e+})}{2} \cdot \sigma_{\text{LR}} \\ & + \frac{(1+P_{e-})}{2} \frac{(1-P_{e+})}{2} \cdot \sigma_{\text{RL}} \\ & + \frac{(1-P_{e-})}{2} \frac{(1-P_{e+})}{2} \cdot \sigma_{\text{LL}} \\ & + \frac{(1+P_{e-})}{2} \frac{(1+P_{e+})}{2} \cdot \sigma_{\text{RR}}\end{aligned}$$

## Experiment:

$$\sigma^{\text{data}}(P_{e-}, P_{e+}) = \frac{N(P_{e-}, P_{e+})}{\mathcal{L}(P_{e-}, P_{e+})}$$

$N$ : number of events

$\mathcal{L}$ : integrated luminosity

Uncertainty via propagation of errors

$$\Delta\sigma^2 = \underbrace{\left(\frac{\partial\sigma}{\partial N}\Delta N\right)^2}_{\text{statistical uncertainty}} + \underbrace{\left(\frac{\partial\sigma}{\partial\mathcal{L}}\Delta\mathcal{L}\right)^2}_{\text{systematical uncertainty}}$$

## Nominal ILC Polarization values

$$\underbrace{P_{e-}^{-} = -80\%},$$

"left"-handed  $e^{-}$ -beam

$$\underbrace{P_{e-}^{+} = 80\%},$$

"right"-handed  $e^{-}$ -beam

$$\underbrace{P_{e+}^{-} = -30\%},$$

"left"-handed  $e^{+}$ -beam

$$\underbrace{P_{e+}^{+} = 30\%},$$

"right"-handed  $e^{+}$ -beam

## ► The 4 ILC polarization configurations

$$\sigma_{-+} := \sigma(P_{e-}^-, P_{e+}^+)$$

$$\sigma_{+-} := \sigma(P_{e-}^+, P_{e+}^-)$$

$$\sigma_{--} := \sigma(P_{e-}^-, P_{e+}^-)$$

$$\sigma_{++} := \sigma(P_{e-}^+, P_{e+}^+)$$

## ► Defining $\chi^2$ function:

$$\chi^2 := \sum_{\text{processes}} \sum_{i,k} \left( \frac{\sigma_{i,k}^{\text{data}} - \sigma_{i,k}^{\text{theory}}(P_{e-}^i, P_{e+}^k)}{\Delta\sigma_{i,k}} \right)^2 \quad i, k \in \{+, -\}$$

## ► Determine the polarization:

- Use  $P_{e-}^-, P_{e-}^+, P_{e+}^-, P_{e+}^+$  as 4 independent parameters
- Find  $P_{e-}^-, P_{e-}^+, P_{e+}^-, P_{e+}^+$  that minimizes  $\chi^2$
- Parameter uncertainties provides also the polarization uncertainties:

$$\Delta P_{e-}^-, \Delta P_{e-}^+, \Delta P_{e+}^-, \Delta P_{e+}^+$$

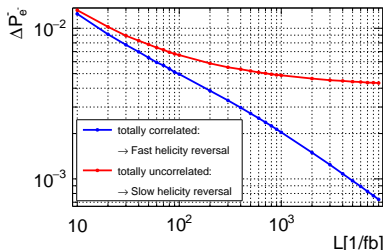


# Systematic Uncertainties and their Correlations

## ▶ Systematic Uncertainties are influenced by

- ▶ Detector calibration and alignment
- ▶ Machine performance
- ▶ ...

## ⇒ Time dependent uncertainties



## ▶ Data set are taken one at a time:

- ▶ Slow frequency of helicity reversals:  $\mathcal{O}$  (weeks to months)
- ▶ Data sets are independent

→ Completely uncorrelated

✗ Lead to saturation at systematic precision

## ▶ Data sets taken concurrently:

- ▶ Fast frequency of helicity reversals:  $\mathcal{O}$  (train-by-train)

→ Faster than changes in calibration/alignment

→ Generate correlations

✓ Lead to cancellation of systematic uncertainties

- ▶ **Polarization provides a deep insight in the chiral structure of the standard model and beyond**
  - ⇒ A permille-level precision of the luminosity-weighted average polarization at the IP is required
- ▶ **Concept for Permille-Level Polarization Precision at the ILC**
  - ▶ The time-resolved beam polarization:
    - ▶ Measured with 2 laser-Compton polarimeters before and after the  $e^-e^+$  IP
    - ▶ Precision of  $\Delta P/P = 0.25\%$  from the start
  - ▶ The luminosity-weighted averaged polarization:
    - ▶ Calculated from cross section measurements of well known standard model processes
    - ▶ Precision of  $\Delta P/P = 0.1\%$  after  $\approx 3$  years of data taking
- ▶ **Impact of time-dependent systematic uncertainties can be reduced due to a fast helicity reversal**

# Backup Slides



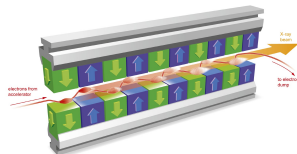
# Production of Polarized Beams

## Electron beam:

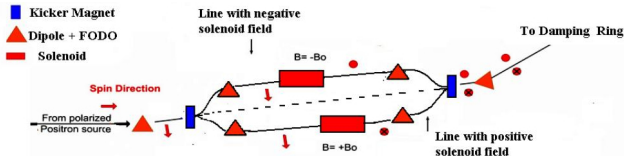
- ▶ Shooting of a circular polarized laser on a photocathode
- ▶ Switch between polarization signs (helicity reversal)
  - ⇒ Switch between signs of the laser polarization

## Positron beam:

- ▶ Production of circular polarized  $\gamma$ 's from  $e^-$ -beam propagating through a helical undulator
  - ⇒  $e^+$  obtained via pair-production of the  $\gamma$ 's
- ▶ Helicity reversal
  - ⇒ Switch between two beam lines



[www.xfel.eu/ueberblick/funktionsweise/](http://www.xfel.eu/ueberblick/funktionsweise/)



## Laser-Compton Polarimeters

Spin Tracking

Collision Data

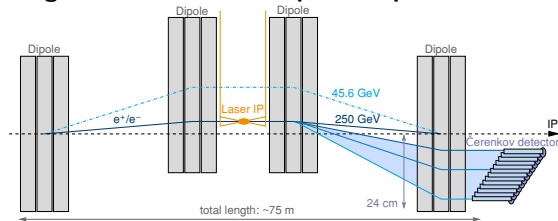
Improvement by Constraints from Polarimeter Measurement

Outlook



# Laser-Compton Polarimeters

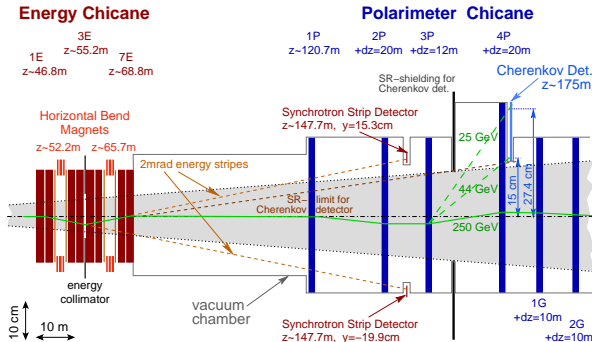
## Magnetic chicane of the upstream polarimeters



- ▶ Compton scattering of the beam with a polarized Laser
- ▶  $\mathcal{O}(10^3)$  particles per bunch ( $2 \cdot 10^{10}$ ) are scattered
- ▶ Magnetic chicane:  
energy spectrum  
⇒ spatial distribution

- ▶ Energy spectrum measurement:  
⇒ Counting the scattered particles at different positions
- ▶ Design of the magnetic Chicane:
  - ▶ Laser-bunch interaction point moves with beam energy  
→ position of the Compton edge stays the same
  - ▶ Orbit of the non-scattered particles is unaffected by the magnetic chicane

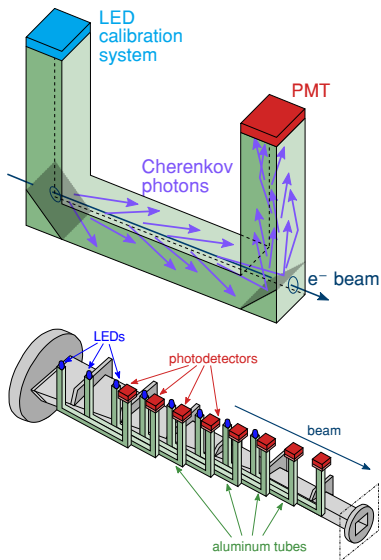
# Downstream Polarimeter



## Difference to Upstream Polarimeter due to a large disturbed beam

- ▶ Stronger banding of the beam after  $\gamma$ -IP
- ▶ 2 additional magnets to restore the beam orbit
- ▶ Measuring one bunch per train

# Cherenkov Detectors: Basic Concept

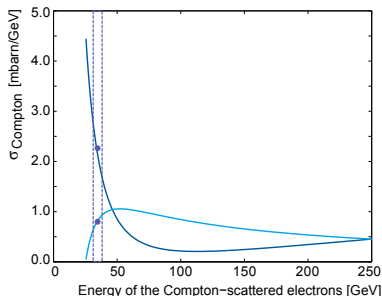


- ▶ U-shape channels filled with gas:  
e.g. perfluorobutane
- ▶ Concept
  - ▶ Scattered particles propagate through the bottom
  - ▶ Produced Cherenkov light is reflected to one end of the channel
  - ▶ Light measurement with photomultiplier tube (PMT)
- ▶ At the other end: LED for PMT calibration
- ▶ Sampling of the energy distribution  
→ Number of Cherenkov detector
- ▶ Energy resolution  
→ Thickness of a Cherenkov detector
- ▶ Quartz Cherenkov detector concept:  
Ref.: Theses Annika Vauth

<http://bib-pubdb1.desy.de/record/171400>



# Differential Compton Cross Section



## Energy dependence:

$$\frac{d\sigma_C}{dy_C} = \frac{2\pi r_e^2}{x_C} (a_C + \lambda \mathcal{P} \cdot b_C); \quad y_C := 1 - \frac{E'}{E}$$

$e^-$  Polarization:  $\mathcal{P}$ ; Laser Polarization:  $\lambda$

DarkBlue:  $\lambda \mathcal{P} = +1$

Cyan:  $\lambda \mathcal{P} = -1$

Calculating  $\mathcal{P}_i$  of the  $i$ -th channel with asymmetry  $A_i$ , analysing power  $\Pi_i$

$$A_i := \frac{N_i^- - N_i^+}{N_i^- + N_i^+}; \quad \Pi_i = \frac{\mathcal{I}_i^- - \mathcal{I}_i^+}{\mathcal{I}_i^- + \mathcal{I}_i^+}; \quad \mathcal{I}_i^\pm := \int_{E_i - \Delta/2}^{E_i + \Delta/2} \frac{d\sigma_C}{dy_C} \Big|_{\lambda \mathcal{P} = \pm 1} dy_C$$

$N^\pm := \#e_{\text{Compton}}$  for  $\lambda \mathcal{P} = \pm 1$ ;  $E_i$ : energy of  $i$ -th channel;  $\Delta$ : energy width

$$\Rightarrow \lambda \mathcal{P}_i = \frac{A_i}{\Pi_i} \quad \Rightarrow \quad \mathcal{P} = \langle \mathcal{P}_i \rangle$$

## Compton Scattering Cross Section: Formulary

$$\frac{d\sigma}{dy_C} = \frac{2\pi r_e^2}{x_C} (a_C + \lambda \mathcal{P} \cdot b_C)$$

$$y_C := 1 - \frac{E'_\gamma}{E}; \quad x_C := \frac{4EE_\gamma}{m_e^2} \cos^2\left(\frac{\vartheta_0}{2}\right)$$

$$r_C := \frac{y_C}{x_C(1 - y_C)}$$

$$a_C := (1 - y_C)^{-1} + 1 - y_C - 4r_C(1 - r_C)$$

$$b_C := r_C x_C (1 - 2r_C)(2 - y_C)$$

$E, E_\gamma$  :  $e^-, \gamma$  energy before Compton scattering

$E', E'_\gamma$  :  $e^-, \gamma$  energy after Compton scattering

$m_e, r_e$  : mass, classical radius of  $e^-$

$\vartheta_0$  : crossing angle between  $e^-, \gamma$

$\mathcal{P}$  : longitudinal polarization of  $e^-$

$\lambda$  : circular polarization of  $\gamma_{\text{Laser}}$

## Characteristic Point:

$$E'_{\text{crossover}} = \frac{E}{1 + x_C/2},$$

$$E'_{\text{ComptonEdge}} = E'_{\text{min}} = \frac{E}{1 + x_C}$$



Laser-Compton Polarimeters

Spin Tracking

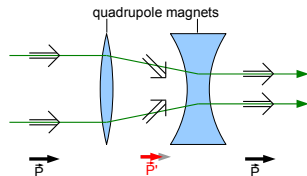
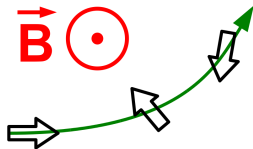
Collision Data

Improvement by Constraints from Polarimeter Measurement

Outlook



# Spin Precession



- ▶ Polarimeters are 1.65 km and 150 m away from IP
  - Particles propagate through magnets
  - Magnets influence the spin, as well
  - Described by Thomas precession

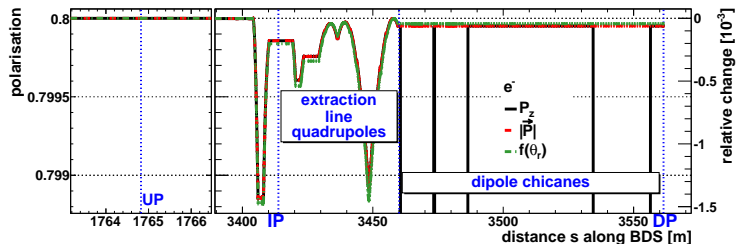
- ▶ if  $\vec{B}_{\parallel} = \vec{E} = 0$ :

$$\frac{d}{dt} \vec{S} = -\frac{q}{m\gamma} \left( (1 + a\gamma) \vec{B}_{\perp} \right) \times \vec{S}$$

- ▶ Effects from focusing and defocusing can cancel
- ▶ For a series of quadrupole magnets  $\mathcal{P}$  described by the angular divergence  $\theta_r$

$$f(\theta_r) = |\vec{\mathcal{P}}|_{\max} \cdot \cos((1 + a\gamma) \cdot \theta_r)$$

## Spin Tracking



## Further causes of longitudinal beam polarization change:

- ▶ *Bremsstrahlung*:  
Deceleration by passing through matter → negligible for colliders
- ▶ *Beamstrahlung*:  
Deflection by the em-field of the oncoming bunch during collision
- ▶ *Synchrotron radiation*:  
Deflection by the em-field of accelerator magnets

# Systematic Polarization Uncertainty

contribution	uncertainty [ $10^{-3}$ ]
Beam and polarization alignment at polarimeters and IP ( $\Delta\vartheta_{\text{bunch}} = 50 \mu\text{rad}$ , $\Delta\vartheta_{\text{pol}} = 25 \text{ mrad}$ )	0.72
Variation in beam parameters (10 % in the emittances)	0.03
Bunch rotation to compensate the beam crossing angle	$< 0.01$
Longitudinal precession in detector magnets	0.01
Emission of synchrotron radiation	0.005
Misalignments ( $10 \mu$ ) without collision effects	0.43
Total (quadratic sum)	0.85
Collision effects in absence of misalignments	$< 2.2$

[Ref.:] Thesis Moritz Beckmann (<http://bib-pubdb1.desy.de/record/155874>)



Laser-Compton Polarimeters

Spin Tracking

Collision Data

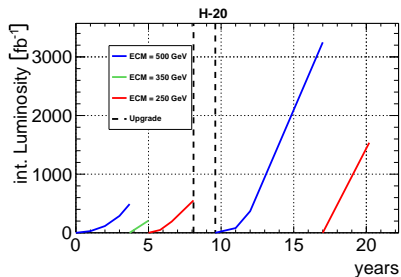
Consider Angular Information by Using differential Cross Section

Improvement by Constraints from Polarimeter Measurement

Outlook



## Reference ILC Running Scenario: H-20



- ▶ Each run have its own polarization measurement
- ⇒ H-20: 5 polarization measurements
- ▶ All plots will refer to ILC nominal energy of 500 GeV

$\sqrt{s}$	(-, +)	(+, -)	(-, -)	(+, +)	$\int L dt$
GeV	[%]	[%]	[%]	[%]	$[\text{fb}^{-1}]$
250	67.5	22.5	5	5	2000
350	67.5	22.5	5	5	200
500	40	40	10	10	4000



# Special Case: The Modified Blondel Scheme (MBS)

## ► Constraints for the Modified Blondel Scheme:

- Process must fulfill:  $\sigma_{LL} \equiv \sigma_{RR} \equiv 0$
- Perfect helicity reversal:  $+|P| \longleftrightarrow -|P| \Rightarrow |P| \equiv \text{const.}$

## ► Unique solution:

4 possible cross section measurements:  $\sigma_{-+}, \sigma_{+-}, \sigma_{--}, \sigma_{++}$

Maximal 4 unknown quantities:  $\sigma_{LR}, \sigma_{RL}, |P_{e-}|, |P_{e+}|$

## ► Solve for $|P_{e\mp}|$ :

$$\sigma_{\pm\pm} = \frac{(1\pm|P_{e-}|)}{2} \frac{(1\mp|P_{e+}|)}{2} \cdot \sigma_{RL} + \frac{(1\mp|P_{e-}|)}{2} \frac{(1\pm|P_{e+}|)}{2} \cdot \sigma_{LR}$$

## ► Modified Blondel-Scheme:

$$|P_{e\mp}| = \sqrt{\frac{(\sigma_{-+} + \sigma_{+-} - \sigma_{--} - \sigma_{++})(\pm\sigma_{-+} \mp \sigma_{+-} + \sigma_{--} - \sigma_{++})}{(\sigma_{-+} + \sigma_{+-} + \sigma_{--} + \sigma_{++})(\pm\sigma_{-+} \mp \sigma_{+-} - \sigma_{--} + \sigma_{++})}}$$

## ► Uncertainties are calculated via analytic error propagation

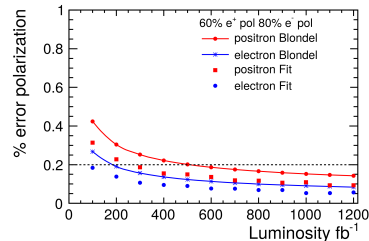
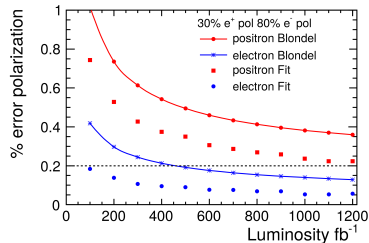
# Previous W-Pair Study by Ivan Marchesini

## W-Pair Production:

- ▶ Using  $e^-e^+ \rightarrow W^+W^- \rightarrow q\bar{q}l\nu$
- ▶ Statistical uncertainties only
- ▶ Consider equal absolute polarizations
- ▶ Including full background study

## Analyses techniques: (overview)

- ▶ Modified Blondel Scheme
- ▶ Angular Fit:
  - ▶ Using a  $\chi^2$ -minimization
  - ▶ Considering the production at different angles
  - ▶ Studied effects on deviations of the absolute polarization value
  - ▶ Measurement of triple gauge couplings



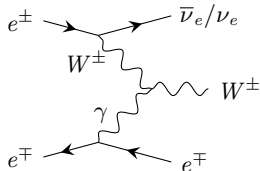
Ref.: Theses Ivan Marchesini

(<http://pubdb.xfel.eu/record/94888>)

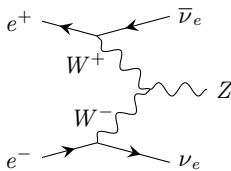


Previous Single  $W^\pm$ ,  $Z$ ,  $\gamma$  Study by Graham W. WilsonSingle  $W^\pm$ 

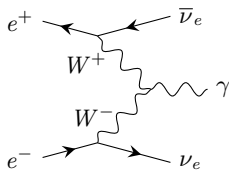
$$e^-e^+ \rightarrow e^\pm \nu \mu^\mp \nu$$

Single  $Z$ 

$$e^-e^+ \rightarrow \nu\bar{\nu}Z$$

Single  $\gamma$ 

$$e^-e^+ \rightarrow \nu\bar{\nu}\gamma$$



#	$P$	$\Delta P/P$
2	$P_{e^-}$	0.07%
	$P_{e^+}$	0.22%
4	$P_{e^-}$	0.085%
	$\delta_{e^-}$	0.12%
	$P_{e^+}$	0.22%
	$\delta_{e^+}$	0.32%

► Using a  $\chi^2$ -minimization

- Total cross sections only
- Simultaneous cross section measurement
- Using 4 processes simultaneously

- Only statistical error with fiducial cuts on cross sections
- Measuring absolute polarization deviation

Ref.: Talk Graham W. Wilson (<https://agenda.linearcollider.org/event/5468/contributions/24027/>)

# Current Work on the Determination of the Polarization from Collision Data

## Goal:

**General strategy for the polarization determination which yields the best precision per measurement time**

- ▶ General and flexible method combining all relevant processes
- ▶ Including all uncertainties and their correlations
- ▶ Compensating for a non-perfect helicity reversal
- ▶ Considering the additional information from the angular distributions
- ▶ Using constraints from the polarimeter measurement for further improvement



# Expected Polarized Cross Section

- Theoretical polarized cross section in general:

$$\begin{aligned}\sigma_{\text{theory}}(P_{e-}, P_{e+}) = & \frac{(1-P_{e-})}{2} \frac{(1-P_{e+})}{2} \cdot \sigma_{\text{LL}} + \frac{(1+P_{e-})}{2} \frac{(1+P_{e+})}{2} \cdot \sigma_{\text{RR}} \\ & + \frac{(1-P_{e-})}{2} \frac{(1+P_{e+})}{2} \cdot \sigma_{\text{LR}} + \frac{(1+P_{e-})}{2} \frac{(1-P_{e+})}{2} \cdot \sigma_{\text{RL}}\end{aligned}$$

- Nominal ILC Polarization values

$$\underbrace{P_{e-}^{-} = -80\%}_{\text{"left"-handed } e^{-}\text{-beam}}$$

$$\underbrace{P_{e-}^{+} = 80\%}_{\text{"right"-handed } e^{-}\text{-beam}}$$

$$\underbrace{P_{e+}^{-} = -30\%}_{\text{"left"-handed } e^{+}\text{-beam}}$$

$$\underbrace{P_{e+}^{+} = 30\%}_{\text{"right"-handed } e^{+}\text{-beam}}$$

- Cross section of the 4 polarization configurations

$$\sigma_{--} := \sigma(P_{e-}^{-}, P_{e+}^{-})$$

$$\sigma_{++} := \sigma(P_{e-}^{+}, P_{e+}^{+})$$

$$\sigma_{-+} := \sigma(P_{e-}^{-}, P_{e+}^{+})$$

$$\sigma_{+-} := \sigma(P_{e-}^{+}, P_{e+}^{-})$$



# Polarized Cross Section Measurement

- Measured polarized cross section:

$$\sigma_{\text{data}} = \frac{D - \mathfrak{B}}{\varepsilon \cdot \mathcal{L}}$$

$D$ : Number of the measured signal events

$\mathfrak{B}$ : Background expectation value

$\varepsilon$ : Selection efficiency of the detector

$\mathcal{L}$ : Integrated luminosity provided by the accelerator

**Remark:** All of them can vary between the different data sets  
 $(\sigma_{--}, \sigma_{++}, \sigma_{-+}, \sigma_{+-})$

- Uncertainty of the polarized cross section calculated via error propagation

$$\Delta\sigma^2 = \left(\frac{\partial\sigma}{\partial D}\Delta D\right)^2 + \left(\frac{\partial\sigma}{\partial\mathfrak{B}}\Delta\mathfrak{B}\right)^2 + \left(\frac{\partial\sigma}{\partial\varepsilon}\Delta\varepsilon\right)^2 + \left(\frac{\partial\sigma}{\partial\mathcal{L}}\Delta\mathcal{L}\right)^2$$

Statistical uncertainty:  $\Delta D = \sqrt{D}$  due to Poisson fluctuations

Systematical uncertainty:  $\Delta\mathfrak{B}, \Delta\varepsilon, \Delta\mathcal{L}$



# Comparison to Previous Analyses (Statistical Uncertainty Only)

$E$	<b>500</b>	<b>250</b>
$\mathcal{L}$	<b>3500</b>	<b>1500</b>
$P_{e-}^-$	0.08	0.09
$P_{e-}^+$	0.02	0.02
$P_{e+}^-$	0.04	0.04
$P_{e+}^+$	0.08	0.08

## Single boson:

- ▶  $\mathcal{L} = 2000 \text{ fb}^{-1}$ ,  $E = 500 \text{ GeV}$
- ▶ No background estimation
- ▶ Fiducial cross section cuts
- ▶ Limitation on  $\delta$ :  $\Delta\delta < 10^{-3}$

$$P_{e-} : 0.085\% \quad \delta_{e-} : 0.12\%$$

$$P_{e+} : 0.22\% \quad \delta_{e+} : 0.32\%$$

$E$	<b>500</b>	<b>350</b>	<b>250</b>
$\mathcal{L}$	<b>500</b>	<b>200</b>	<b>500</b>
$P_{e-}^-$	0.2	0.3	0.1
$P_{e-}^+$	0.05	0.06	0.03
$P_{e+}^-$	0.1	0.1	0.06
$P_{e+}^+$	0.2	0.3	0.1

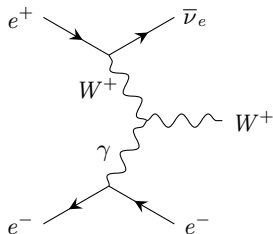
## W-pairs:

- ▶  $\mathcal{L} = 500 \text{ fb}^{-1}$ ,  $E = 500 \text{ GeV}$
- ▶ Full background estimation
- ▶ Differential cross section (angular fit)
- ▶ Only using 2 free parameters

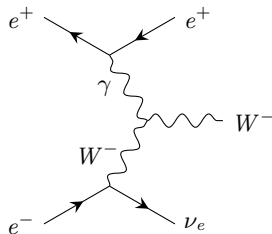
$$P_{e-} : 0.08\% \quad P_{e+} : 0.34\%$$

# Previous Single $W^\pm$ , $Z$ , $\gamma$ Study: Leading Diagrams

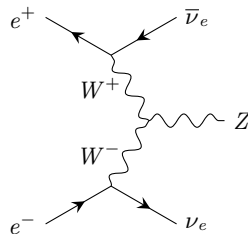
## Single $W^+$



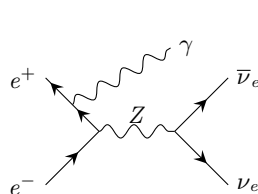
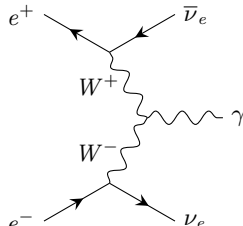
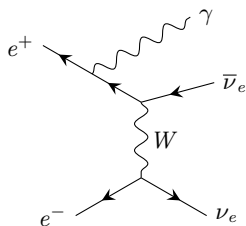
## Single $W^-$



## Single $Z$



## Single $\gamma$





# Comparison to the Previous W-Pair Study

## Study by Ivan Marchesini:

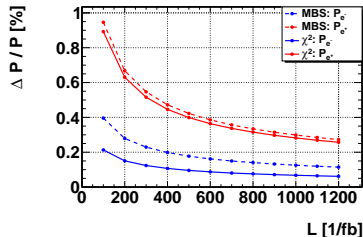
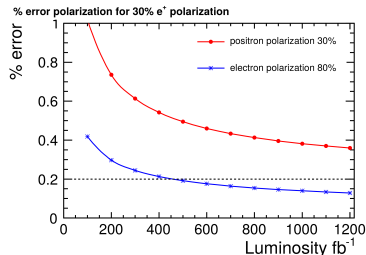
- ▶ Using  $e^-e^+ \rightarrow W^+W^- \rightarrow q\bar{q}l\nu$
- ▶ Statistical uncertainties only
- ▶ Consider equal absolute polarizations (MBS)
- ▶ Including full background study

## Adjustment of the current study:

- ▶ Limited to  $e^-e^+ \rightarrow W^+W^- \rightarrow q\bar{q}l\nu$
- ▶ Forced equal absolute polarizations ( $|P^L| \equiv |P^R|$ )
- ▶ Including same background estimation and selection efficiency

## Comparison:

- ⇒  $\chi^2$ -method yields better precision under same conditions than the MBS



# Comparison to Previous Single $W^\pm, \gamma, Z$ Study

## Study by Graham W. Wilson

- Using 4 Processes simultaneously:

$$e^- e^+ \rightarrow \nu \bar{\nu} \gamma; \quad e^- e^+ \rightarrow \nu \bar{\nu} Z$$

$$e^- e^+ \rightarrow e^+ \nu W^- \rightarrow e^+ \nu \mu^- \bar{\nu}$$

$$e^- e^+ \rightarrow e^- \bar{\nu} W^+ \rightarrow e^- \bar{\nu} \mu^+ \nu$$

- Consider equal absolute polarizations  
2 Parameters:  $P_{e^-}, P_{e^+}$
- Consider deviations: 4 Parameters

$$P_{e^\pm}^L = -|P_{e^\pm}| + \frac{1}{2}\delta_\pm$$

$$P_{e^\pm}^R = |P_{e^\pm}| + \frac{1}{2}\delta_\pm$$

## Comparison to Current analysis

- Differences:

**Previous:** Constraint on  $\delta$ :  $\Delta\delta < 10^{-3}$

**Current:** direct fit of  $P_{e^\pm}^{L,R}$

parameters		$\Delta P/P, \mathcal{L} = 2\text{ab}^{-1}$	
#	$P$	Previous	Current
2	$P_{e^-}$	0.07%	0.051%
	$P_{e^+}$	0.22%	0.21%
4	$P_{e^-}$	0.085%	0.088%
	$\delta_{e^-}$	0.12%	0.19%
	$P_{e^+}$	0.22%	0.23%
	$\delta_{e^+}$	0.32%	0.56%

$\mathcal{L}$  equally distributed between  $\sigma_{\pm\pm}$

Statistical precision only

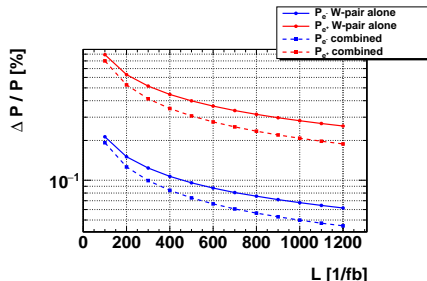
- Very similar precision even without additional constraint on  $\delta$



# Combining W-Pair + Single $W, Z, \gamma$

## Combined vs. W-Pairs alone

- ▶ W-Pair yields only enough information for 2 parameter fit  $P_{e-}, P_{e+}$
  - ▶ Large improvement  
→ due to additional processes
  - ▶ Combined: fit of 4 parameters is possible  $P_{e-}^L, P_{e-}^R, P_{e+}^L, P_{e+}^R$
- ⇒ Compensation for a non-perfect helicity reversal



$$\Delta P/P, \mathcal{L} = 2\text{ab}^{-1}$$

	single $W, Z, \gamma$	Combined
$P_{e-}$	0.088%	0.079%
$\delta_{e-}$	0.19%	0.18%
$P_{e+}$	0.23%	0.16%
$\delta_{e+}$	0.56%	0.51%

## Combined vs. Single Boson

- ▶ The 4 processes Single  $W^{\pm}$ , Single  $Z$ , Single  $\gamma$  yields a large analysis power
- ▶ Combined precision dominated by single boson processes

# $\chi^2$ -Minimization

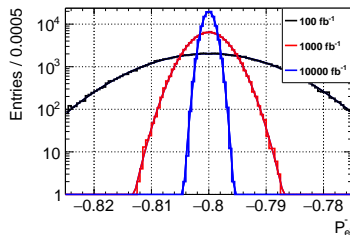
## ► Defining $\chi^2$ function:

$$\chi^2 := \sum_{\text{process}} \sum_{\pm\pm} \frac{(\sigma_{\text{data}} - \sigma_{\text{theory}}(P_{e-}^-, P_{e-}^+, P_{e+}^-, P_{e+}^+))^2}{\Delta\sigma^2}$$

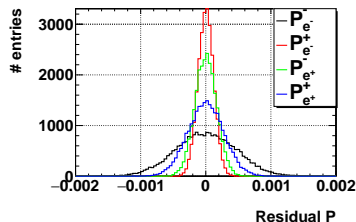
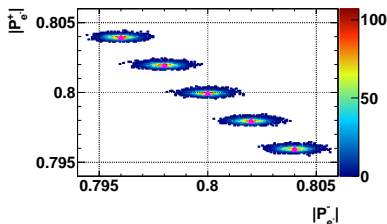
## ► Varying $(P_{e-}^-, P_{e-}^+, P_{e+}^-, P_{e+}^+)$ $\rightarrow$ Minimizes $\chi^2$

## ► Toy measurement:

- Signal expectation value:  
 $\langle D \rangle = \sigma_{\text{theory}} \cdot \varepsilon \cdot \mathcal{L} + \mathfrak{B}$
- One toy experiment:  
 Random Poisson number around each  $\langle D \rangle$
- Determine  $P_{e\pm}^\pm$  by minimizing  $\chi^2$
- Simplified case for illustration:
  - $\mathfrak{B} = 0$  and  $\varepsilon = 1$
  - Statistical uncertainties only
  - Using  $10^5$  toy measurements



# Testing for a Non-Perfect Helicity Reversal



## ► Variation in the absolute polarization

- Toy Measurement for 5 different polarization discrepancies for both beams
- Nominal initial polarizations:  $|P_{e-}| = 80\%$ ,  $|P_{e+}| = 30\%$
- Statistical uncertainties only

## ► $\chi^2$ -Fit:

- Correct determination of the 4 polarization values
- No noticeable impact on polarization precision using total cross sections

✓ **Can compensate for a non-perfect helicity reversal**

# Theoretical Limit of the Statistical Precision

## Consider most relevant processes:

Process	Channel
single $W^\pm$	$e\nu l\nu, e\nu q\bar{q}$
$WW$	$q\bar{q}q\bar{q}, q\bar{q}l\nu, l\nu l\nu$
$ZZ$	$q\bar{q}q\bar{q}, q\bar{q}ll, llll$
$ZZWW$ Mix	$q\bar{q}q\bar{q}, l\nu l\nu$
$Z$	$q\bar{q}, ll$

- ▶ Same processes as for physics analysis (DBD)
- ▶ Tree-level cross sections + ISR
- ▶ Any combination of processes can be used
- ▶ Further process can easily added

## Consider best case scenario using $\sigma_{\text{tot}}$ :

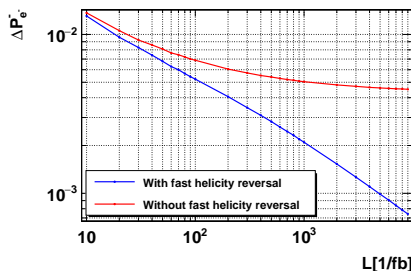
- ▶ Assumption of a perfect  $4\pi$  detector
- ▶ No background
- ▶ No systematic uncertainties
- ▶ Using all considered processes

## Statistical precision H-20: $\Delta P/P$ [%]

$E$	500	350	250	500	250
$\mathcal{L}$	500	200	500	3500	1500
$P_{e-}^-$	0.2	0.3	0.1	0.08	0.09
$P_{e-}^+$	0.05	0.06	0.03	0.02	0.02
$P_{e+}^-$	0.1	0.1	0.06	0.04	0.04
$P_{e+}^+$	0.2	0.3	0.1	0.08	0.08

# Systematic Uncertainties and their Correlations

Systematic quantity		related to:
Integrated luminosity	$\mathcal{L}$	accelerator
Selection efficiency	$\varepsilon$	detector
Background estimate	$\mathfrak{B}$	theory



## Remark:

A non-perfect helicity reversal has close to no influence on the precision due to compensation

## ► Uncertainties influenced by

- Detector calibration and alignment
  - Machine performance
  - $\mathfrak{B}$  assumed constant and small
- ⇒  $\Delta\mathcal{L}$ ,  $\Delta\varepsilon$  are time dependent

## ► One data set at a time:

- Data sets are independent
  - Completely uncorrelated
- ⇒ Lead to saturation at systematic precision

## ► Fast helicity reversal:

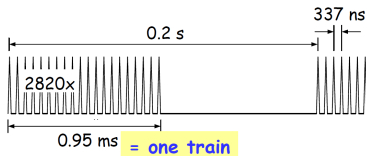
- Data sets taken concurrently
  - Generate correlations
- ⇒ Lead to cancellation of systematic uncertainties

# Generation of Correlated Uncertainties: Fast Helicity Reversal

## Generation of Correlated Uncertainties

- ⇒ Change between data sets ( $\sigma_{-+}$ ,  $\sigma_{+-}$ ,  $\sigma_{--}$ ,  $\sigma_{++}$ ) faster than change in detector and accelerator calibration
- ⇒ Change between data sets during normal run without additional breaks

## ILC Bunch Structure



## Two possible frequency:

- ▶ bunch-by-bunch: switch between two bunches
  - ▶ train-by-train: switch between two trains
- ▶ Technical feasibility much easier for train-by-train
  - ▶ Switch train-by-train should be sufficient for polarization precision
- ⇒ Precise correlation coefficient still to do



# Implementing Correlated Uncertainties

$$\chi^2 = \sum_{\text{process}} (\vec{\sigma}_{\text{data}} - \vec{\sigma}_{\text{theory}})^T \Xi^{-1} (\vec{\sigma}_{\text{data}} - \vec{\sigma}_{\text{theory}}); \quad \vec{\sigma} := (\sigma_{-+} \quad \sigma_{+-} \quad \sigma_{--} \quad \sigma_{++})^T$$

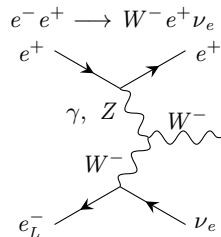
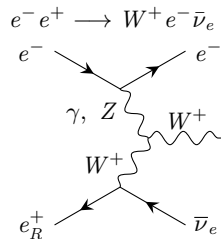
$$\Xi := \Xi_D + \Xi_{\mathfrak{B}} + \Xi_{\varepsilon} + \Xi_{\mathcal{L}}; \quad \text{e.g. } (\Xi_{\varepsilon})_{ij} = \text{corr}(\vec{\sigma}_i^{\varepsilon}, \vec{\sigma}_j^{\varepsilon}) \frac{\partial \vec{\sigma}_i}{\partial \varepsilon_i} \frac{\partial \vec{\sigma}_j}{\partial \varepsilon_j} \Delta \varepsilon_i \Delta \varepsilon_j$$

- ▶ Using the inverse covariance matrix  $\Xi^{-1}$
- ▶ Correlation coefficients:
  - ▶ Identical for each process
  - ▶ Can be different for each quantity ( $\mathfrak{B}$ ,  $\varepsilon$ ,  $\mathcal{L}$ )
  - ▶ Statistical uncertainties are always uncorrelated  $\text{corr}(\vec{\sigma}_i^D, \vec{\sigma}_j^D) = 0 \quad \forall i \neq j$
  - ▶ Correlation coefficients are no free parameter  
 $\Rightarrow$  They are an external input parameter

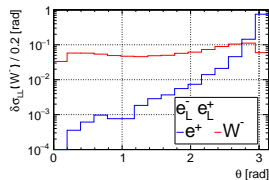
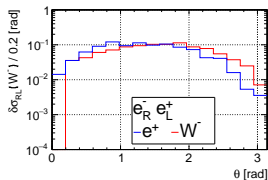
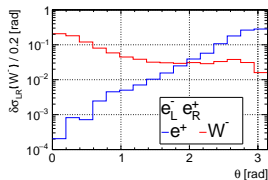
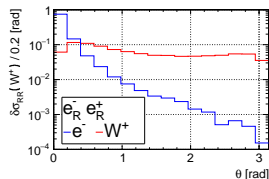
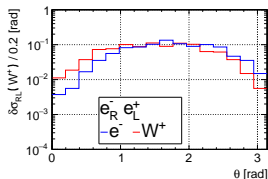
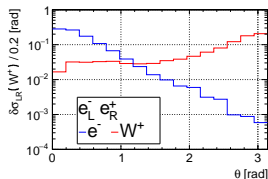


# Consideration of the Addition Information from the Angular Distribution

- ▶ Total cross section
  - ▶ Rely on theoretical calculation
  - ⇒ Susceptible to BSM effects
- ▶ Differential cross section
  - ▶ Additional usage of the angular information
  - ⇒ Increase of the robustness against BSM effects
- ▶ Starting with Single W Process
  - ▶ Angular distribution has a large dependence on the chirality
  - ▶ Separated in  $W^+$  and  $W^-$  production
  - ⇒ Sensitive to individual beam polarization
    - ▶  $W^+$ : only sensitive to  $P_{e+}$
    - ▶  $W^-$ : only sensitive to  $P_{e-}$
- ▶ Further processes can easily be included



# Single $W^\pm$ : Polar Production Angle Distribution



## ► Single differential cross section: $\partial\sigma/\partial\theta$

- Two independent angles:  $\theta_e$ ,  $\theta_W$
- For now start with  $\theta_e \rightarrow e^\pm$  also needed for separation between  $W^\pm$

## ► $\partial\sigma/\partial\theta$ will be calculated via $\Delta\sigma_i/\Delta\theta_i$ ("cross section for the $i$ -th bin in $\theta$ ")

# Defining Differential Cross Sections

## Measured cross section:

$$\overbrace{\frac{\partial \sigma}{\partial \theta}}^{\text{differential cross section}} \longrightarrow \overbrace{\delta_i \sigma_{\text{data}}}^{\text{cross section per } i\text{th bin}} := \frac{\delta_i D - \delta_i \mathfrak{B}}{\delta_i \varepsilon \cdot \mathcal{L}}$$

$$\left. \begin{array}{ll} \delta_i D & \text{Number of signal events} \\ \delta_i \mathfrak{B} & \text{Number of expected background events} \\ \delta_i \varepsilon & \text{Selection efficiency} \\ \mathcal{L} & \text{Integrated luminosity} \end{array} \right\} \text{ of the } i\text{th bin}$$

## Theoretical cross section:

$$\begin{aligned} \delta_i \sigma_{\pm\pm} &= \frac{\binom{1 \pm |P_{e-}^{\pm}|}{2}}{\binom{1 \pm |P_{e+}^{\pm}|}{2}} \delta_i \sigma_{RR} + \frac{\binom{1 \mp |P_{e-}^{\pm}|}{2}}{\binom{1 \mp |P_{e+}^{\pm}|}{2}} \delta_i \sigma_{LL} \\ &+ \frac{\binom{1 \pm |P_{e-}^{\pm}|}{2}}{\binom{1 \mp |P_{e+}^{\pm}|}{2}} \delta_i \sigma_{RL} + \frac{\binom{1 \mp |P_{e-}^{\pm}|}{2}}{\binom{1 \pm |P_{e+}^{\pm}|}{2}} \delta_i \sigma_{LR} \\ \delta_i \sigma_{\text{theory}} &:= f(\theta_i) \cdot \sigma_{\text{theory}} \end{aligned}$$

$f(\theta_i)$  is directly obtained from the angular distributions

# Implementing Differential Cross Sections in the $\chi^2$ Minimization

**Replacing:**  $\sigma \longrightarrow \delta_k \sigma + \text{Sum over all bins}$

$$\chi^2 = \sum_{\text{process}} \sum_{\theta_k} (\delta_k \vec{\sigma}_{\text{data}} - \delta_k \vec{\sigma}_{\text{theory}})^T (\delta_k \Xi)^{-1} (\delta_k \vec{\sigma}_{\text{data}} - \delta_k \vec{\sigma}_{\text{theory}})$$

$$\delta_k \vec{\sigma} := \begin{pmatrix} \delta_k \sigma_{-+} & \delta_k \sigma_{+-} & \delta_k \sigma_{--} & \delta_k \sigma_{++} \end{pmatrix}^T$$

$$\delta_k \Xi := \delta_k \Xi_N + \delta_k \Xi_{\mathfrak{B}} + \delta_k \Xi_{\varepsilon} + \delta_k \Xi_{\mathcal{L}};$$

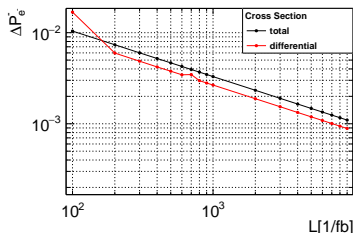
$$(\delta_k \Xi_{\varepsilon})_{ij} = \text{corr}(\vec{\sigma}_i^{\varepsilon}, \vec{\sigma}_j^{\varepsilon}) \frac{\partial (\delta_k \vec{\sigma}_i)}{\partial (\delta_k \varepsilon_i)} \frac{\partial (\delta_k \vec{\sigma}_j)}{\partial (\delta_k \varepsilon_j)} \Delta(\delta_k \varepsilon_i) \Delta(\delta_k \varepsilon_j)$$

**Remarks:**

- ▶ Due to correlations, the binning in  $\theta$  has to be equal for all cross sections
- ▶ It can differ between processes and decay-channels
- ▶ Range and number of bins of  $\theta$  can be changed externally for each process

# First Toy Measurements: Preliminary Results

## Single $W^\pm$ only



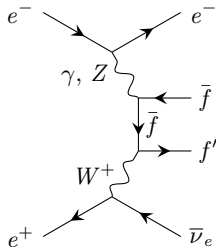
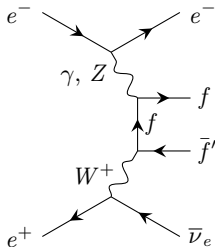
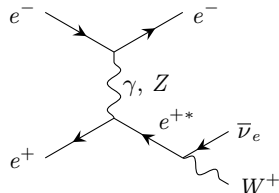
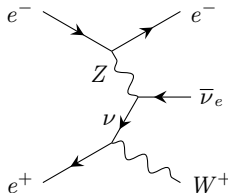
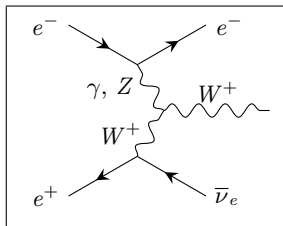
## Using the following configuration:

- ▶ Using 16 equal bins in a  $\theta$  range of  $[0, \pi]$
- ▶ Signal determination bin-by-bin:  

$$\langle \delta_k D \rangle = \delta_k \sigma_{\text{theory}} \cdot \delta_k \varepsilon \cdot \mathcal{L} + \delta_k \mathfrak{B}$$
- ▶ For the start:  
 Statistical error only + no background
- ▶ Using H-20 integrated luminosity sharing due to energy

- ▶ Differential cross section have a lower statistic uncertainty:
  - ▶ Expectation of  $\delta_k D$  can be for some bins  $\mathcal{O}(1)$
  - ▶ Some zero diagonal entries of the covariance matrix  $\rightarrow$  not invertible
  - $\Rightarrow$  Dropping  $\chi^2$ -terms with  $\delta_k D = 0$
- ▶ Further steps:
  - ▶ Optimizing the  $\theta$  range and binning
  - ▶ Including further processes

# Contributions to "Actual" Single W Production



Polarization dependence:

► Positrons:

⇒ only right-handed:  $e_R^+$

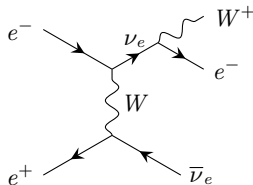
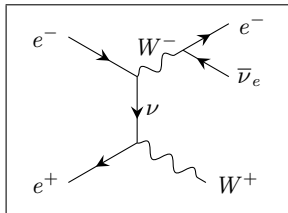
► Electrons:

►  $e_L^- + e_R^-$

► difference for  $\gamma, Z$

# Further Contributions to Single W Production

Contribution from t-channel process:



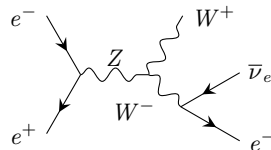
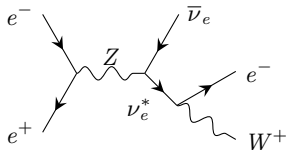
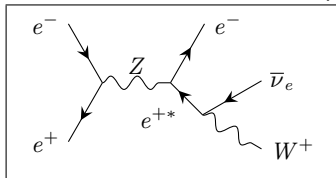
► t-channel contributions:

- W-pair production
- W exchange

► Polarization dependence:

- only  $e_R^+$
- + only  $e_L^-$

Contribution from s-channel Z process ( only for opposite chirality ):





# Usage of the Differential Polarized Cross Section

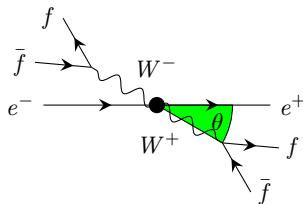
## ► Total cross section

- Rely on theoretical calculation
- ⇒ Susceptible to BSM effects

## ► Differential cross section

- Additional usage of the angular information
- ⇒ Increase of the robustness against BSM effects

e.g.:  $e^+e^- \rightarrow W^+W^- \rightarrow q\bar{q}l\nu$

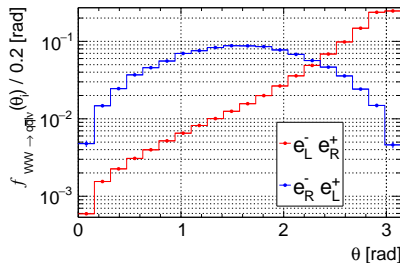


Bin-wise cross section calculation:

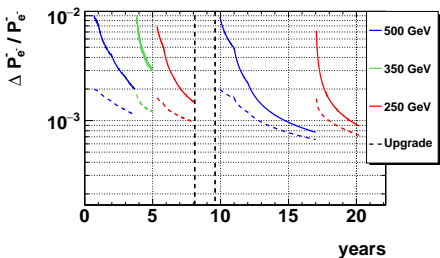
$$\begin{aligned} \underbrace{\frac{\partial \sigma}{\partial \theta}}_{\text{differential cross section}} &\longrightarrow \underbrace{\delta_i \sigma_{\text{data}}}_{\text{cross section of the } i\text{-th bin}} := \delta_i N / \mathcal{L} \\ &\longrightarrow \delta_i \sigma_{LR} := f_{LR}(\theta_i) \cdot \sigma_{LR} \end{aligned}$$

Analog:  $RL, LL, RR$

- $\delta_i N$ : events of  $i$ -th bin
- $f(\theta_i)$ : fraction of the total cross section



# Consider Constraints from the Polarimeter Measurement



## Simplified approach: (as a first step)

- ▶ Neglect spin transport
- ▶ Using  $\Delta P/P = 0.25\%$ :
- ▶ Gaussian distribution
  - ▶ Mean:  $|P_{e-}| = 80\%, |P_{e+}| = 30\%$
  - ▶ Width:  $\Delta P$

## Implementation:

$$\chi^2_{+} = \sum_P \left[ \frac{(P_{e\pm}^{\pm} - \mathcal{P}_{e\pm}^{\pm})^2}{\Delta \mathcal{P}^2} \right]$$

- ▶  $P_{e\pm}^{\pm}$ : 4 fitted parameters
- ▶  $\mathcal{P}_{e\pm}^{\pm}$ : Polarimeter measurement
- ▶  $\Delta \mathcal{P}$ : Polarimeter uncertainty

$E$	500	350	250	500	250
$\mathcal{L}$	500	200	500	3500	1500
Without Constraint					
$P_{e-}^{-}$	0.2	0.3	0.1	0.08	0.09
With Constraint					
$P_{e-}^{-}$	0.1	0.1	0.1	0.07	0.07

$E$	500	350	250	500	250
$\mathcal{L}$	500	200	500	3500	1500
<b>Without Constraint</b>					
$P_{e-}^-$	0.2	0.3	0.1	0.08	0.09
$P_{e-}^+$	0.05	0.06	0.03	0.02	0.02
$P_{e+}^-$	0.1	0.1	0.06	0.04	0.04
$P_{e+}^+$	0.2	0.3	0.1	0.08	0.08
<b>With Constraint</b>					
$P_{e-}^-$	0.1	0.1	0.1	0.07	0.07
$P_{e-}^+$	0.04	0.05	0.03	0.02	0.02
$P_{e+}^-$	0.09	0.09	0.05	0.04	0.03
$P_{e+}^+$	0.1	0.1	0.09	0.07	0.07

# Systematic Uncertainty Calculation

## Selection Efficiency $\varepsilon$

- ▶ Realistic values for  $\varepsilon$  and  $\Delta\varepsilon$  still missing
- ▶  $\varepsilon$  values for:
  - ▶ W-pair production: Thesis Ivan
  - ▶ Single W: Accessible due to the work of our former intern Sebastian Garcia

## Expected Background Prediction $\mathfrak{B}$

- ▶ Background estimate  $\mathfrak{B} \pm \Delta\mathfrak{B}$  is also missing for each process
- ▶ Full background analysis for every process is not feasible
- ▶  $WW \rightarrow qql\nu$ :  $\mathfrak{B}$  can be taken from Ivan's thesis
  - ⇒ Assuming similar  $\mathfrak{B}$  for other boson pair



# Simultaneous Fitting of chiral cross sections

Similar to G. Wilson's single boson study:

$$\begin{pmatrix} \sigma_{LR}^{\gamma} & \sigma_{LR}^Z & \sigma_{LR}^{\mu} & \sigma_{LR}^{\mu} \\ \sigma_{RL}^{\gamma} & 0.465 & 0.066 & 0.066 \\ 0.0 & 0.0 & \sigma_{SS}^{\mu} & 0.0 \\ 0.0 & 0.0 & 0.0 & \sigma_{SS}^{\mu} \end{pmatrix}$$

Ongoing Work for the current study:

- ▶ Implementing of free linear cross section scaling parameters
- ▶ Each chiral cross section can be scaled individually or fixed
- ▶ Chiral cross section can have the same scaling parameter
- ▶ Which cross section is scaled will be changeable

## 7-parameter single boson fit

2 ab<sup>-1</sup> equally distributed  
(statistical errors only)

$$|P_{e-}| = 80.000 \pm 0.056\%$$

$$|P_{e-}| = 30.000 \pm 0.065\%$$

$$\sigma_{LR}^{\gamma} = 3098.0 \pm 2.7 \text{ fb}$$

$$\sigma_{RL}^{\gamma} = 25.3 \pm 1.1 \text{ fb}$$

$$\sigma_{LR}^Z = 159.40 \pm 0.57 \text{ fb}$$

$$\sigma_{LR}^{\mu} = 580.9 \pm 1.1 \text{ fb}$$

$$\sigma_{SS}^{\mu} = 657.4 \pm 1.1 \text{ fb}$$

Beam polarizations correlation:

$$\rho(|P_{e-}|, |P_{e-}|) = 14\%$$